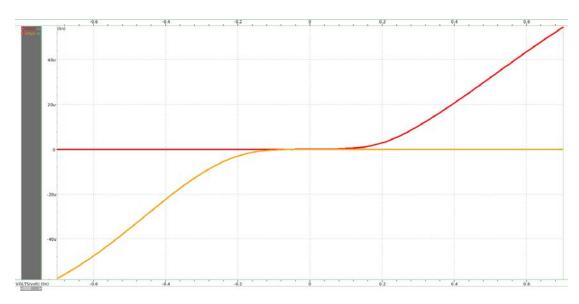
Exercise 1-1: DC characteristics (25%)

- Simulate DC characteristics of FinFETs and planer MOSs by minimal feature sizes
 - ◆ Vgs-los of FinFET (N-FinFET & P-FinFET) in one figure
 ➤ Number of Fin = 1
 ➤ Vdd = 0.7v
 - Vgs-IDS of CMOS (NMOS & P-MOS)in one figure
 ➤ minimal width and Length = 16nm
 ➤ Vdd = 0.7v

1_a:

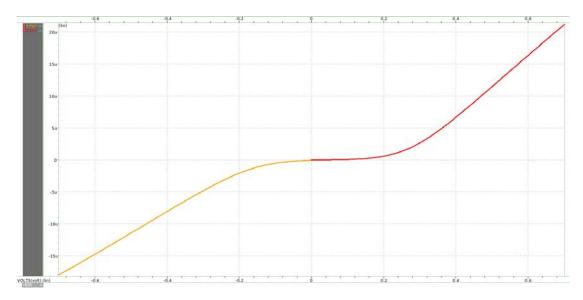
設計 FINFET(N-FinFET & P-FinFET)的 V_{GS} -IDS 圖,FinFET 數量=1, VDD=0.7V。 下圖為將一 DC 電壓源(V_{GS})從 -0.7V 線性升至 0.7V,並觀察 V_{GS} -IDS 圖,可以發現通過 P-FinFET(mp,橋線)的電流隨著 V_{GS} 上升而趨近於 0,反而是通過 N-FinFET(mn,紅線)的電流隨著 V_{GS} 上升而逐漸增加,而電流若從 Drain 端到 Source 端定為正,因此 P-FinFET 的電流為負。



FINFET(N-FinFET & P-FinFET)的 V_{GS}-I_{DS} 圖

1_b:

設計 MOSFET(NMOS & PMOS)的 V_{GS} - I_{DS} 圖,MOS 數量=1,VDD=0.7V。 此題與上題類似,只是將 P-FinFET 改為 PMOS,N-FinFET 改為 NMOS,把尺寸設為 16nm 以後便可以得到下方 V_{GS} - I_{DS} 圖。與上方相似,可以發現通過 PMOS(mp,橋線)的電流隨著 V_{GS} 上升而趨近於 0,反而是通過 NMOS(mn,紅線)的電流隨著 V_{GS} 上升而逐漸增加,與上題比較可以發現,MOSFET 的電流會比 FinFET 來的小。



Planer MOSFET(NMOS & PMOS)的 VGS-IDS 圖

Exercise 1-2: Voltage Transfer Curve (25%)

- Select the smallest and largest inverters from ASAP 7nm standard cell library and simulate the voltage transfer characteristic (VTC).
 - ◆ Netlist of standard cells: asap7sc7p5t INVBUF RVT.sp
 - ◆ Plot VTC curves of these 2 inverters under different voltages (Vdd = 0.7V, 0.6V, 0.5V and 0.4V)

2_a:

我們從助教提供的 library 中選出最大與與最小的 inverter 分別是 INVx13_ASAP7_75t_R 以及 INVxp33_ASAP7_75t_R,判斷依據是看 Width,因為發現他們 Length 皆相同,由結果可以得知,最小 size 的 inverter 與最大 size 的 inverter 的 VTC 曲線近乎相同,而若 VDD 的輸入較小,也會使 switching point 發生的電壓變小。

Voutxp33(smallest inverter):

nmos_rvt: L=2e-08m , W=2.7e-08m , nfin=1 pmos_rvt: L=2e-08m , W=2.7e-08m , nfin=1

```
*

* VSS VSS

* VDD VDD

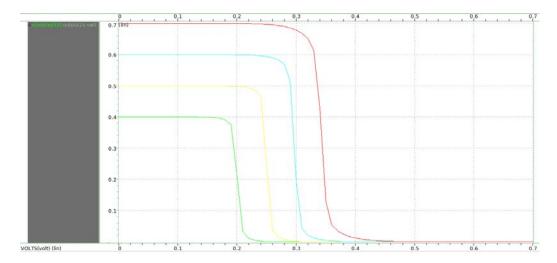
* A A

* Y Y

*

MM0 N_MM0_d N_MM0_g VSS VSS nmos_rvt L=2e-08 W=2.7e-08 nfin=1

MM1 N_MM1_d N_MM0_g VDD VDD pmos_rvt L=2e-08 W=2.7e-08 nfin=1
```



最小 size 的 inverter 之 VTC curve

voutX13(largest inverter):

nmos_rvt: L=2e-08m , W=8.1e-08m , nfin=3 pmos_rvt: L=2e-08m , W=8.1e-08m , nfin=3

```
.SUBCKT:INVx13_ASAP7_75t_R VSS VDD A Y

*

* VSS VSS

* VDD VDD

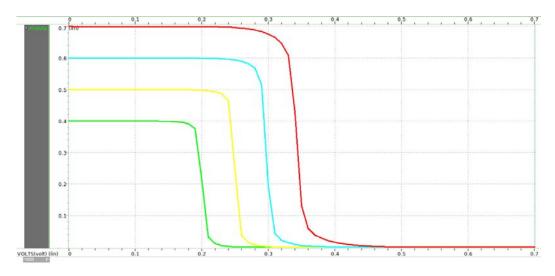
* A A

* Y Y

*

MM0 N_MM0_d N_MM0_g VSS VSS nmos_rvt L=2e-08 W=8.1e-08 nfin=3

MM0@13 N_MM0@13_d N_MM1@13_g VSS VSS nmos_rvt L=2e-08 W=8.1e-08 nfin=3
```

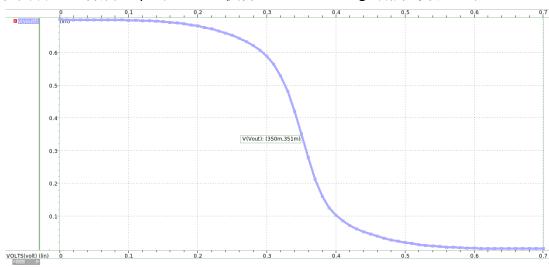


最大 size 的 inverter 之 VTC curve

- Design unit-sized inverters such that their logic threshold voltage is at $\frac{Vdd}{2}$ (vdd = 0.7v)
 - ◆ Plot the VTC curve
 - ➤ Using FinFETs (7nm_TT.pm)
 - ➤ Using Planer MOSs (16mos.pm)

2_b: FinFET:

藉由調 NFin 數目: mp=6, mn=5,使得 threshold voltage 剛好等於 VDD/2=350mV

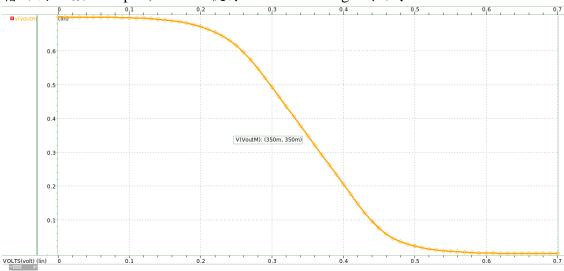


FinFET VTC curve

P-FinFET: W=7nm $\,^{,}$ L=7nm $\,^{,}$ nFin=6 $\,^{,}$ N-FinFET: W=7nm $\,^{,}$ L=7nm $\,^{,}$ nFin=5 Logic threshold voltage = 0.351V

MOS:

藉由調 m 數目: mp=7, mn=5, 使得 threshold voltage 剛好等於 VDD/2=350mV



Planer MOS VTC curve

PMOS: W=16nm \cdot L=16nm \cdot m=7 ; NMOS: W=16nm \cdot L=16nm \cdot m=5 Logic threshold voltage = 0.35V

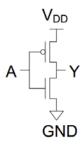
Inverter 的 VTC curve 發生轉折處會隨 K_n/K_p 的大小而改變,當 MOS/FinFET 的 size 固定,透過調整 mos/Fin 的並聯數目 m,等同調整等效的 W,故可調整 V_{th} 。當 pmos 的 m 增加,等效的 Wp 增加,Kp 增加。當 nmos 的 m 增加,等效的 Wn 增加,Kn 增加。

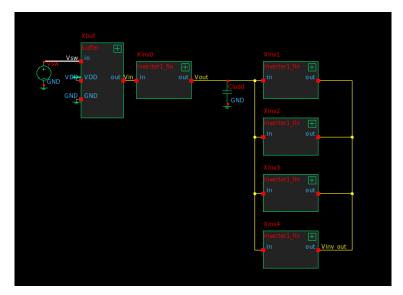
當 Kn>Kp, 曲線會往左移動, logic threshold voltage 降低。

當 Kn<Kp, 曲線會往右移動, logic threshold voltage 增加。

Exercise 1-3: Power consumption (25%)

- Measure the power consumption of the inverters, designed in 1-2.
 - ◆ Input buffer: Buffer.sp
 - ◆ Output loading: FO4 (4 inverters) + 10 fF as wire loading
- \blacklozenge Vdd = 0.7v
- ◆ Input pattern need more than 20.
- Input signal switching frequency
 - ➤ 1GHz
 - ≥2GHz
 - ►4GHz





模擬電路示意圖

INV_FinFET:

Input signal switching frequency = 1GHz:

```
***** transient analysis tnom= 25.000 temp= 25.000 *****

static_pwr= 7.4902u from= 0. to= 20.0000n

| ***** job concluded
```

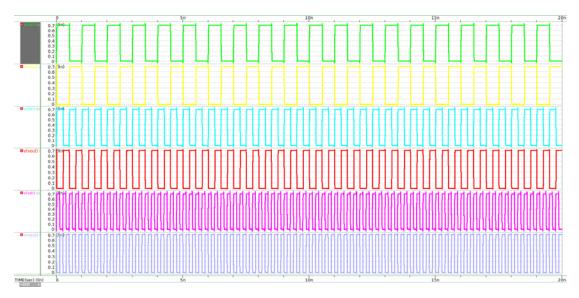
Input signal switching frequency = 2GHz:

Input signal switching frequency = 4GHz:

```
***** transient analysis tnom= 25.000 temp= 25.000 *****

static_pwr= 29.9249u from= 0. to= 20.0000n

| | | | ***** job concluded
```



Y 軸依序為 Vin(1GHz)、Vout(1GHz)、Vin(2GHz)、Vout(2GHz)、Vin(4GHz)、Vout(4GHz)

3_b:

INV_MOS:

Input signal switching frequency = 1GHz:

```
title hw3_b

****** transient analysis tnom= 25.000 temp= 25.000 *****

static_pwr= 9.9285u from= 0. to= 20.0000n

| | | ***** job concluded

******
```

Input signal switching frequency = 2GHz:

```
title hw3_b

***** transient analysis tnom= 25.000 temp= 25.000 *****

static_pwr= 18.7971u from= 0. to= 20.0000n

| | ***** job concluded
```

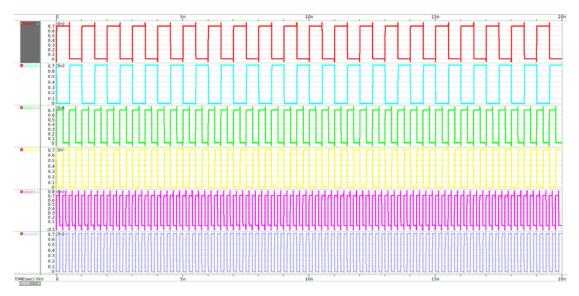
Input signal switching frequency = 4GHz:

```
******

title hw3_b

****** transient analysis tnom= 25.000 temp= 25.000 ******

static_pwr= 34.2670u from= 0. to= 20.0000n
```



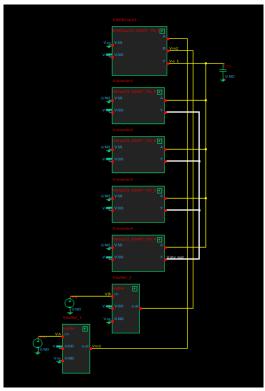
Y 軸依序為 Vin(1GHz)、Vout(1GHz)、Vin(2GHz)、Vout(2GHz)、Vin(4GHz)、Vout(4GHz)

當 input signal switching frequency 增加,測量相同時間的 power consumption,可發現隨著 input signal switching frequency 上升,因為經過更多個 cycles,因此 power consumption 變大。

Exercise 1-4: Characteristics of NOR2/NAND2 (25%)

- Select the smallest NOR2 and NAND2 from ASAP 7nm standard cell library
- ◆ Input buffer: Buffer.sp
- ◆ Output loading: FO4 (4 inverters) + 10 fF as wire loading
 ➤ Inverter: smallest inverters in ASAP 7nm standard cell library
- Netlist of standard cells:
 ➤ asap7sc7p5t_INVBUF_RVT.sp
 ➤ asap7sc7p5t_SIMPLE_RVT.sp
- ◆ Vdd = 0.7v
- ◆ Measure Tr, Tf, Tplh, Tphl

4_a:



模擬電路示意圖

NAND2:

```
* hw1_4a

***** transient analysis tnom= 25.000 temp= 25.000 *****

tr= 227.6794p targ= 2.3447n trig= 2.1170n

tf= 191.1884p targ= 1.7516n trig= 1.5604n

tplh= 145.8436p targ= 2.2208n trig= 2.0750n

tphl= 108.1338p targ= 1.6331n trig= 1.5250n

propogation_delay= 126.9887p
```

Tr = 227.6494ps , Tf = 191.1884ps , Tplh = 145.8436ps , Tphl = 108.1338ps

NOR2:

```
hw1_4a

***** transient analysis tnom= 25.000 temp= 25.000 *****

tr= 283.4089p targ= 2.8649n trig= 2.5814n

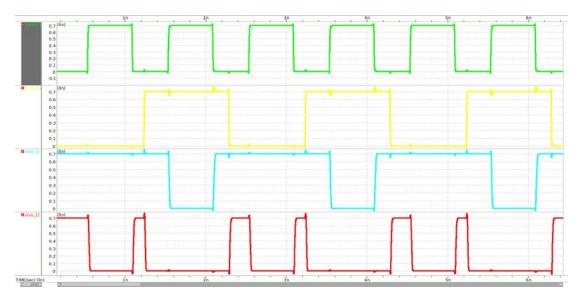
tf= 226.7527p targ= 1.2835n trig= 1.0567n

tplh= 185.9399p targ= 2.6859n trig= 2.5000n

tphl= 144.7894p targ= 1.1448n trig= 1.0000n

propogation_delay= 165.3646p
```

Tr = 283.4089ps , Tf = 226.7527ps , Tplh = 185.9399ps , Tphl = 144.7894ps



Y 軸依序為 INA、INB、Vout1(NAND 的輸出)、Vout2(NOR 的輸出)

Propagation delay 為 Ron(turn-on resistance)和 C_L (parasitic capacitance on output node)的函數,delay 正比於 R_n*C_L ,代表 R_n 越大或 C_L 越大,delay 會越大。